

## Description

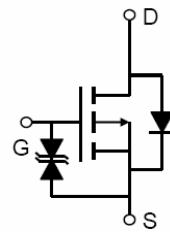
The VSM18P10 uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications. It is ESD protected.

## General Features

- $V_{DS} = -100V, I_D = -18A$
- $R_{DS(ON)} < 100m\Omega @ V_{GS} = -10V$  (Typ:  $85m\Omega$ )
- $R_{DS(ON)} < 120m\Omega @ V_{GS} = -10V$  (Typ:  $95m\Omega$ )
- Super high dense cell design
- Advanced trench process technology
- Reliable and rugged
- High density cell design for ultra low On-Resistance

## Application

- Power management in notebook computer
- Portable equipment and battery powered systems



TO-263

Schematic Diagram

## Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
VSM18P10-T3	VSM18P10	TO-263	-	-	-

## Absolute Maximum Ratings ( $T_c=25^\circ C$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	$V_{DS}$	-100	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current-Continuous	$I_D$	-18	A
Drain Current-Continuous( $T_c=100^\circ C$ )	$I_D (100^\circ C)$	-12	A
Pulsed Drain Current	$I_{DM}$	-100	A
Single pulse avalanche energy <sup>(Note 5)</sup>	$E_{AS}$	170	mJ
Maximum Power Dissipation	$P_D$	70	W
Derating factor		0.47	W/ $^\circ C$
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 To 175	$^\circ C$

## Thermal Characteristic

Thermal Resistance, Junction-to-Case <sup>(Note 2)</sup>	$R_{\theta JC}$	2.14	$^\circ C/W$
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**Electrical Characteristics ( $T_c=25^\circ\text{C}$  unless otherwise noted)**

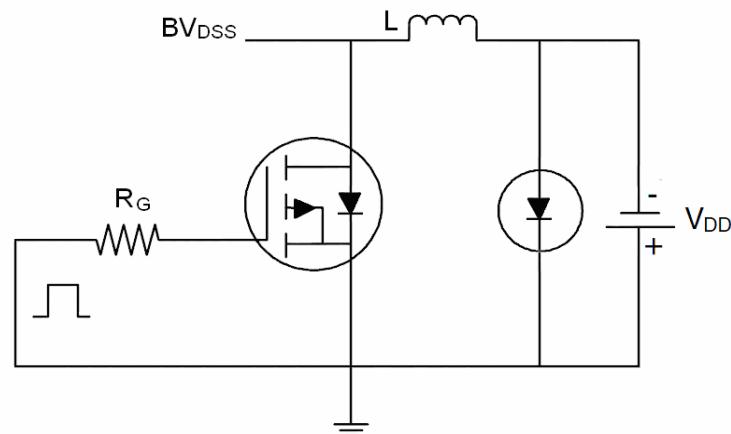
Parameter	Symbol	Condition	Min	Typ	Max	Unit
<b>Off Characteristics</b>						
Drain-Source Breakdown Voltage	$\text{BV}_{\text{DSS}}$	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_D=-250\mu\text{A}$	-100	-	-	V
Zero Gate Voltage Drain Current	$\text{I}_{\text{DSS}}$	$\text{V}_{\text{DS}}=-100\text{V}, \text{V}_{\text{GS}}=0\text{V}$	-	-	1	$\mu\text{A}$
Gate-Body Leakage Current	$\text{I}_{\text{GSS}}$	$\text{V}_{\text{GS}}=\pm20\text{V}, \text{V}_{\text{DS}}=0\text{V}$	-	-	$\pm20$	$\mu\text{A}$
<b>On Characteristics</b> (Note 3)						
Gate Threshold Voltage	$\text{V}_{\text{GS(th)}}$	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_D=-250\mu\text{A}$	-1	-1.9	-3	V
Drain-Source On-State Resistance	$\text{R}_{\text{DS(ON)}}$	$\text{V}_{\text{GS}}=-10\text{V}, \text{I}_D=-16\text{A}$	-	85	100	$\text{m}\Omega$
		$\text{V}_{\text{GS}}=-4.5\text{V}, \text{I}_D=-16\text{A}$		95	120	
Forward Transconductance	$\text{g}_{\text{FS}}$	$\text{V}_{\text{DS}}=-50\text{V}, \text{I}_D=-10\text{A}$	5	-	-	S
<b>Dynamic Characteristics</b> (Note 4)						
Input Capacitance	$\text{C}_{\text{iss}}$	$\text{V}_{\text{DS}}=-50\text{V}, \text{V}_{\text{GS}}=0\text{V}, \text{F}=1.0\text{MHz}$	-	3810	-	PF
Output Capacitance	$\text{C}_{\text{oss}}$		-	129	-	PF
Reverse Transfer Capacitance	$\text{C}_{\text{rss}}$		-	125	-	PF
<b>Switching Characteristics</b> (Note 4)						
Turn-on Delay Time	$t_{\text{d(on)}}$	$\text{V}_{\text{DD}}=-50\text{V}, \text{I}_D=-16\text{A}, \text{V}_{\text{GS}}=-10\text{V}, \text{R}_{\text{GEN}}=9.1\Omega$	-	16	-	nS
Turn-on Rise Time	$t_r$		-	73	-	nS
Turn-Off Delay Time	$t_{\text{d(off)}}$		-	34	-	nS
Turn-Off Fall Time	$t_f$		-	57	-	nS
Total Gate Charge	$\text{Q}_g$	$\text{V}_{\text{DS}}=-50\text{V}, \text{I}_D=-16\text{A}, \text{V}_{\text{GS}}=-10\text{V}$	-	70	-	nC
Gate-Source Charge	$\text{Q}_{\text{gs}}$		-	12.5	-	nC
Gate-Drain Charge	$\text{Q}_{\text{gd}}$		-	15.5	-	nC
<b>Drain-Source Diode Characteristics</b>						
Diode Forward Voltage (Note 3)	$\text{V}_{\text{SD}}$	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_s=-10\text{A}$	-	-	-1.2	V
Diode Forward Current (Note 2)	$\text{I}_s$	-	-	-	-18	A
Reverse Recovery Time	$t_{\text{rr}}$	$\text{TJ} = 25^\circ\text{C}, \text{IF} = -16\text{A}$ $\text{di/dt} = 100\text{A}/\mu\text{s}$ (Note 3)	-	88.3	-	nS
Reverse Recovery Charge	$\text{Q}_{\text{rr}}$		-	65.9	-	nC
Forward Turn-On Time	$t_{\text{on}}$	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

**Notes:**

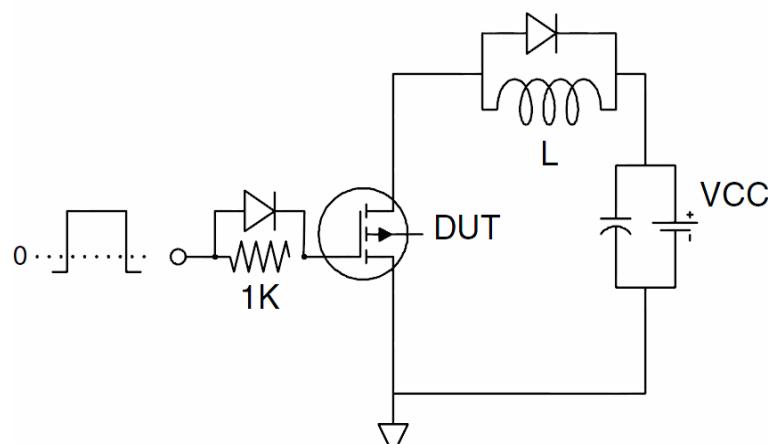
1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board,  $t \leq 10$  sec.
3. Pulse Test: Pulse Width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$ .
4. Guaranteed by design, not subject to production
5. EAS condition:  $\text{Tj}=25^\circ\text{C}, \text{V}_{\text{DD}}=-50\text{V}, \text{V}_{\text{G}}=-10\text{V}, \text{L}=0.5\text{mH}, \text{R}_g=25\Omega$

## Test Circuit

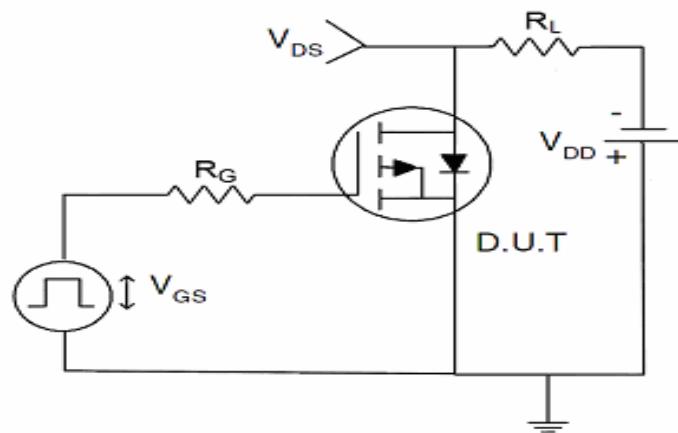
### 1) E<sub>AS</sub> Test Circuit



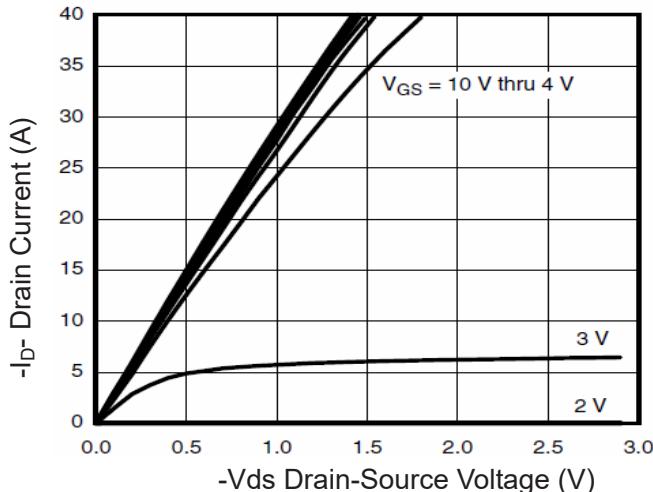
### 2) Gate Charge Test Circuit



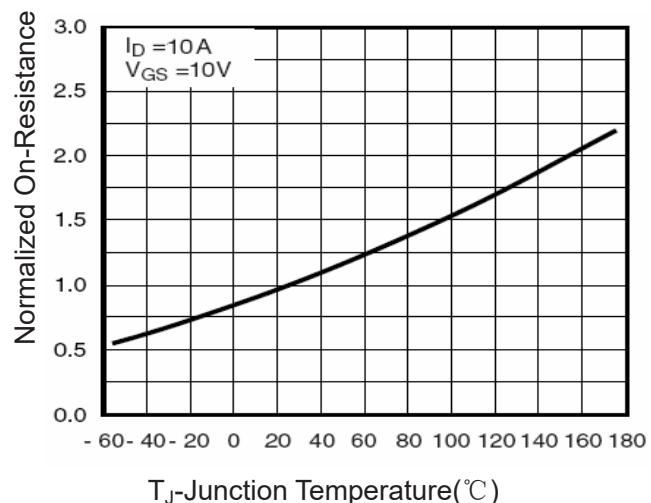
### 3) Switch Time Test Circuit



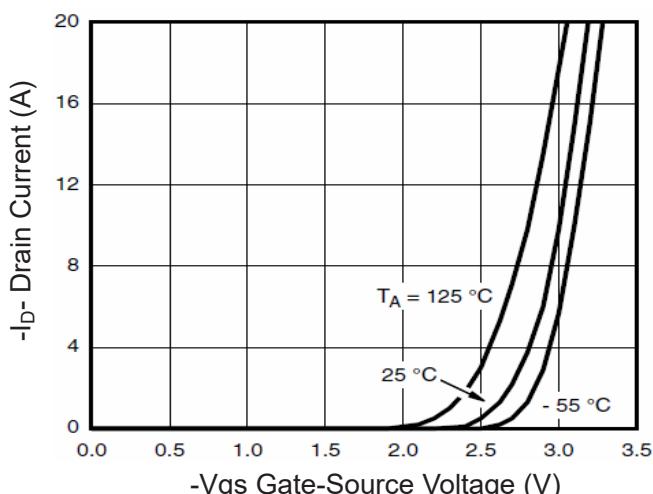
## Typical Electrical and Thermal Characteristics (Curves)



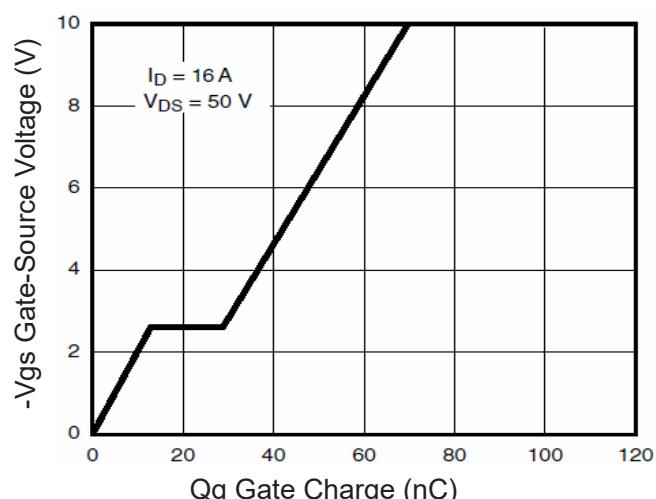
**Figure 1 Output Characteristics**



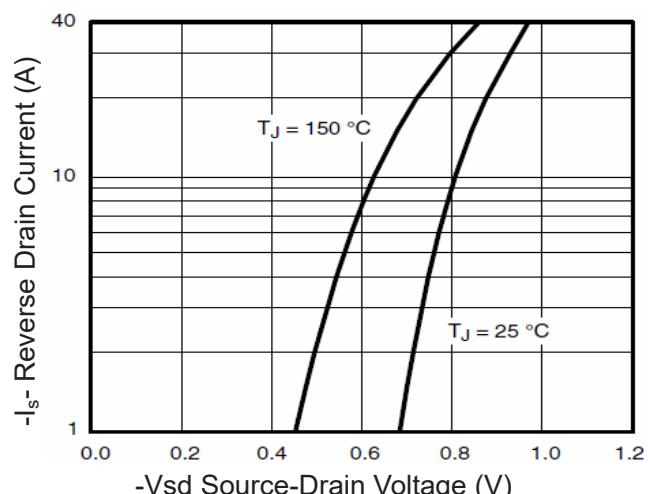
**Figure 4 Rdson-JunctionTemperature**



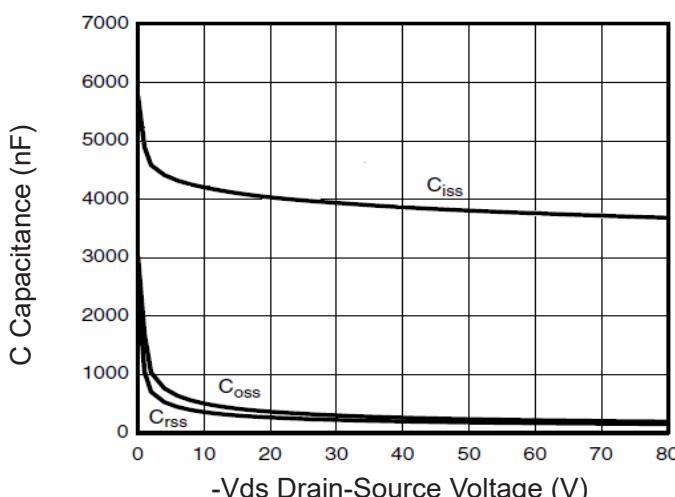
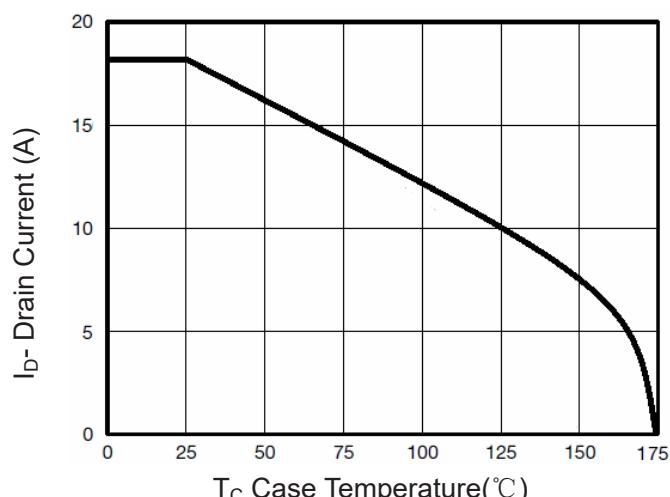
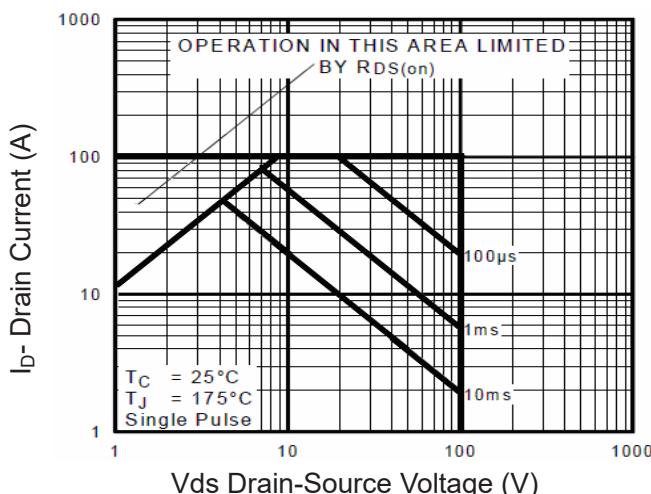
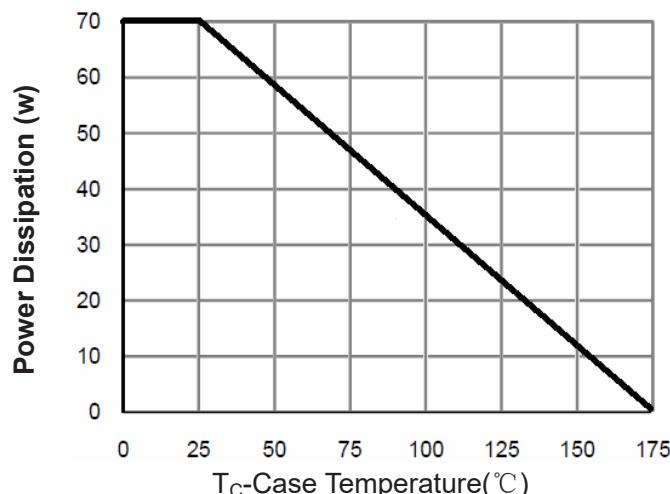
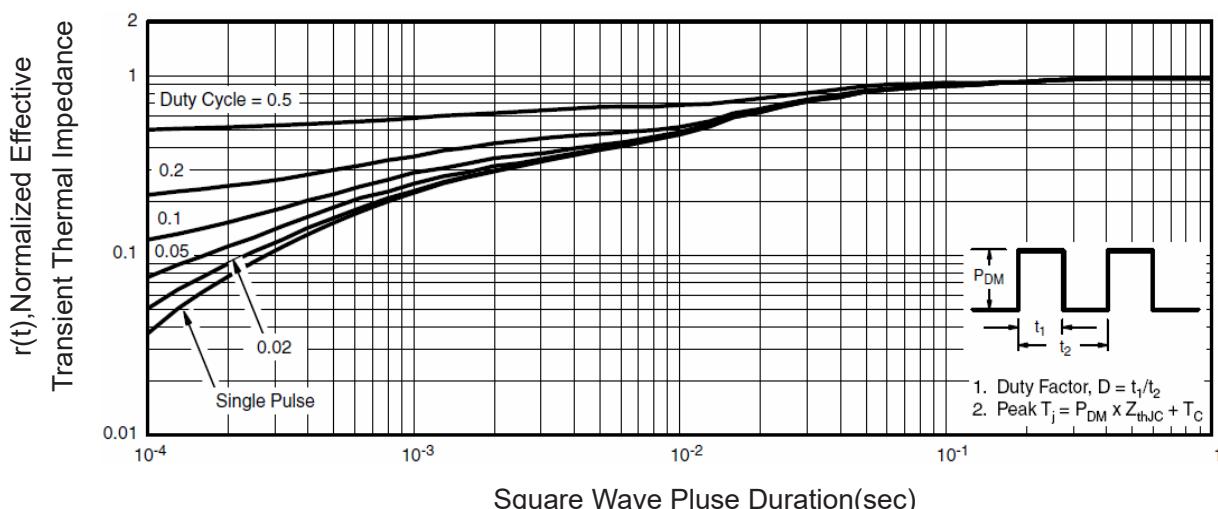
**Figure 2 Transfer Characteristics**



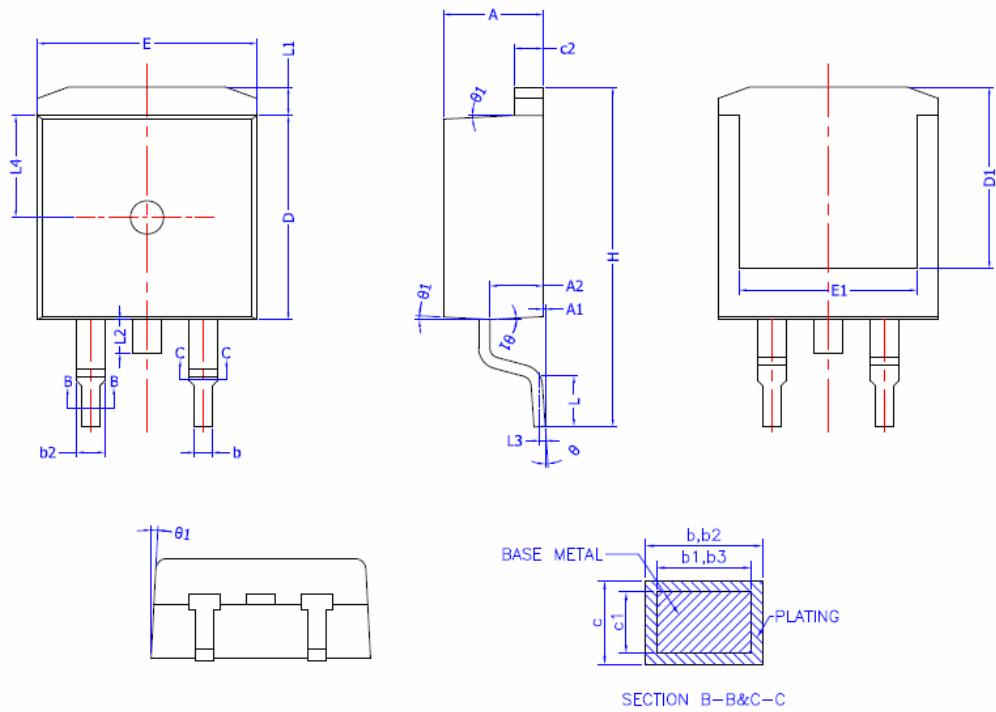
**Figure 5 Gate Charge**



**Figure 6 Source- Drain Diode Forward**


**Figure 7 Capacitance vs Vds**

**Figure 9 Drain Current vs Case Temperature**

**Figure 8 Safe Operation Area**

**Figure 10 Power De-rating**

**Figure 11 Normalized Maximum Transient Thermal Impedance**

## TO-263-2L Package Information



**COMMON DIMENSIONS**  
(UNITS OF MEASURE = MILLIMETER)

SYMBOL	MIN	NOM	MAX
A	4.40	4.50	4.60
A1	0	0.10	0.25
A2	2.20	2.40	2.60
b	0.76	—	0.89
b1	0.75	0.80	0.85
b2	1.23	—	1.37
b3	1.22	1.27	1.32
c	0.47	—	0.60
c1	0.46	0.51	0.56
c2	1.25	1.30	1.35
D	9.10	9.20	9.30
D1	8.00	—	—
E	9.80	9.90	10.00
E1	7.80	—	—
e	2.54 BSC		
H	14.90	15.30	15.70
L	2.00	2.30	2.60
L1	1.17	1.27	1.40
L2	—	—	1.75
L3	0.25BSC		
L4	4.60 REF		
θ	0°	—	8°
θ1	1°	3°	5°